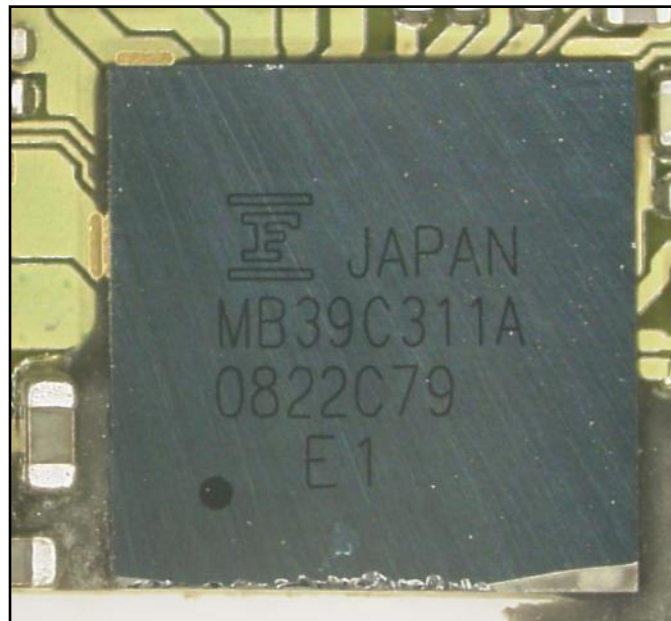


Reverse Costing analysis



EWLP 309-pin by Casio Micronics – Fujitsu MB39C311A The largest Full Wafer Level Chip Scale Package

June 2010- Version 2

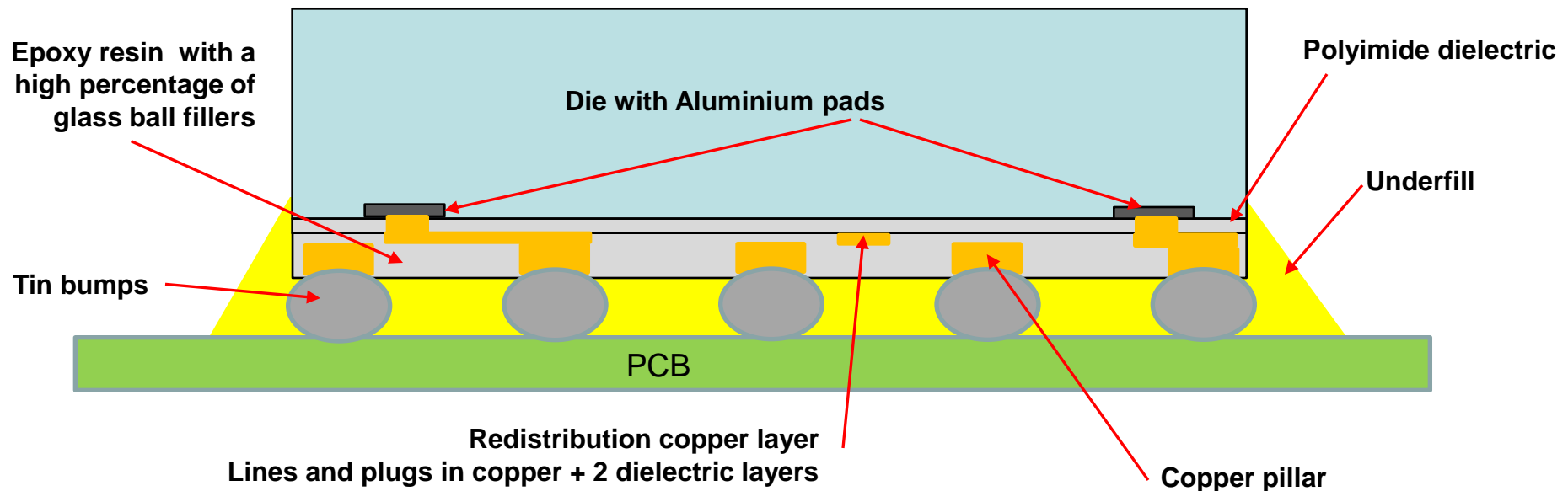
Written by: Sylvain HALLEREAU

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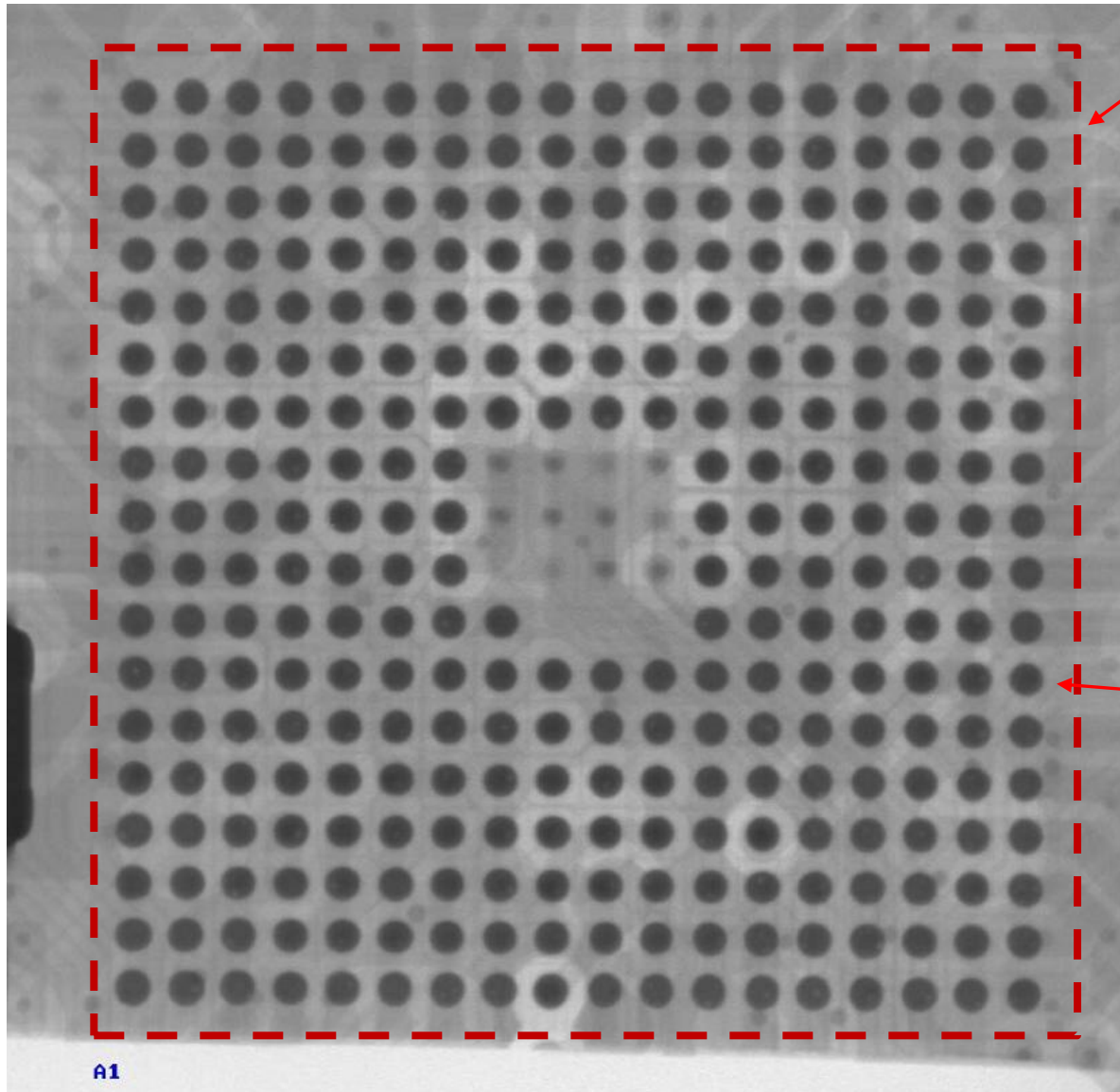
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• WL-CSP Process Flow			
• Redistribution and copper post			
• Bumping and Dicing			

- Package is analyzed and measured.
 - X-ray pictures are used to identify the package construction and the redistribution.
- One cross-section is realized to get overall package data : dimensions, main characteristics.
- Analysis of used technology and materials is provided.

The schematic diagram below is based on the observations made during this study and detailed in the next slides.



This X-Ray picture of WL-CSP with the PCB.

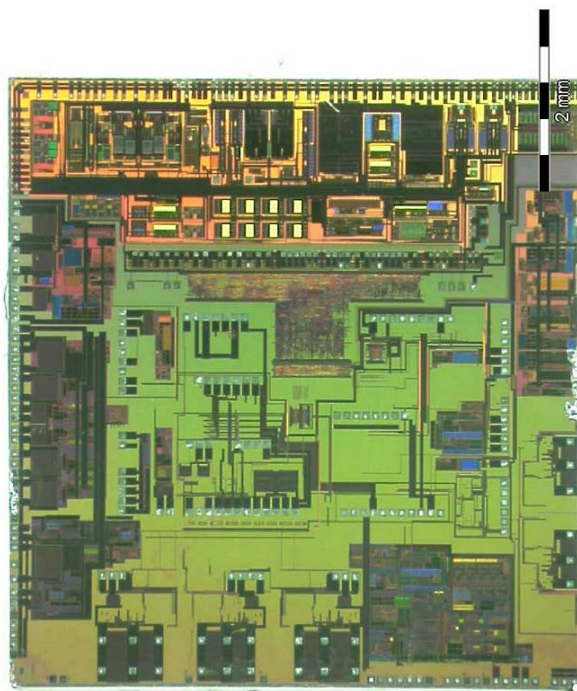
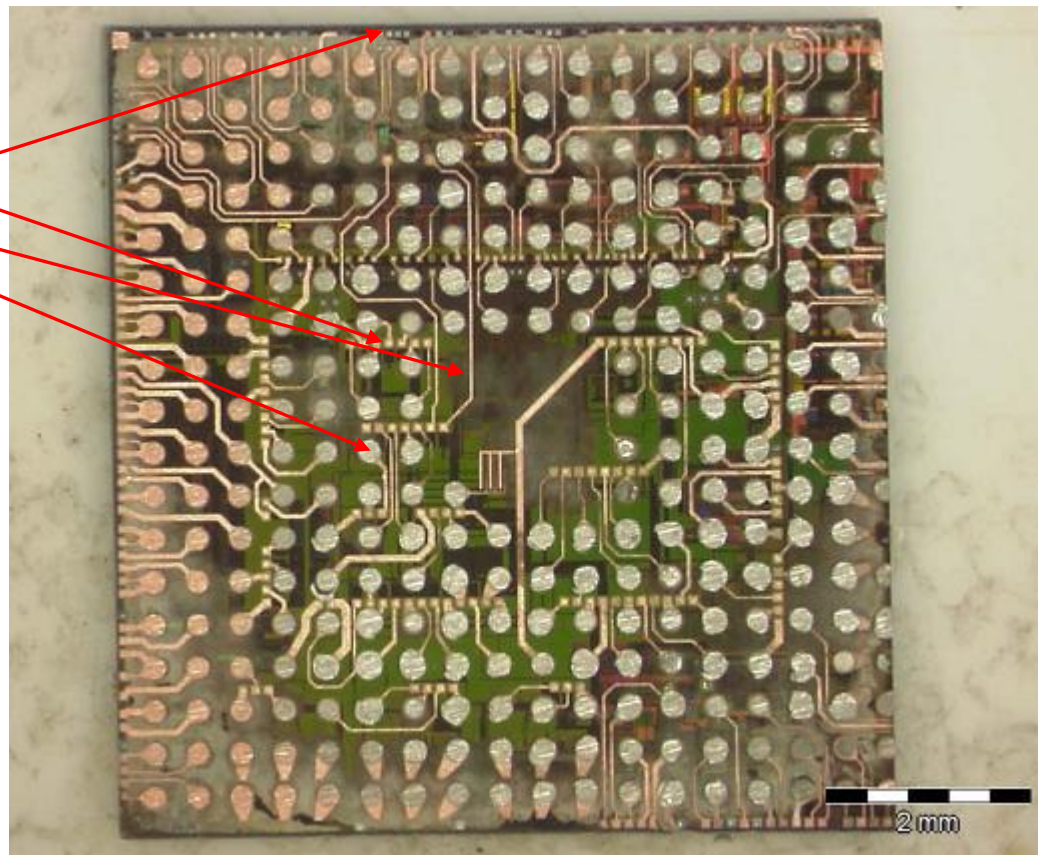


Die
7.45mm x 7.45mm = 55.5mm²

250µm between the side of the die
and the first balls.

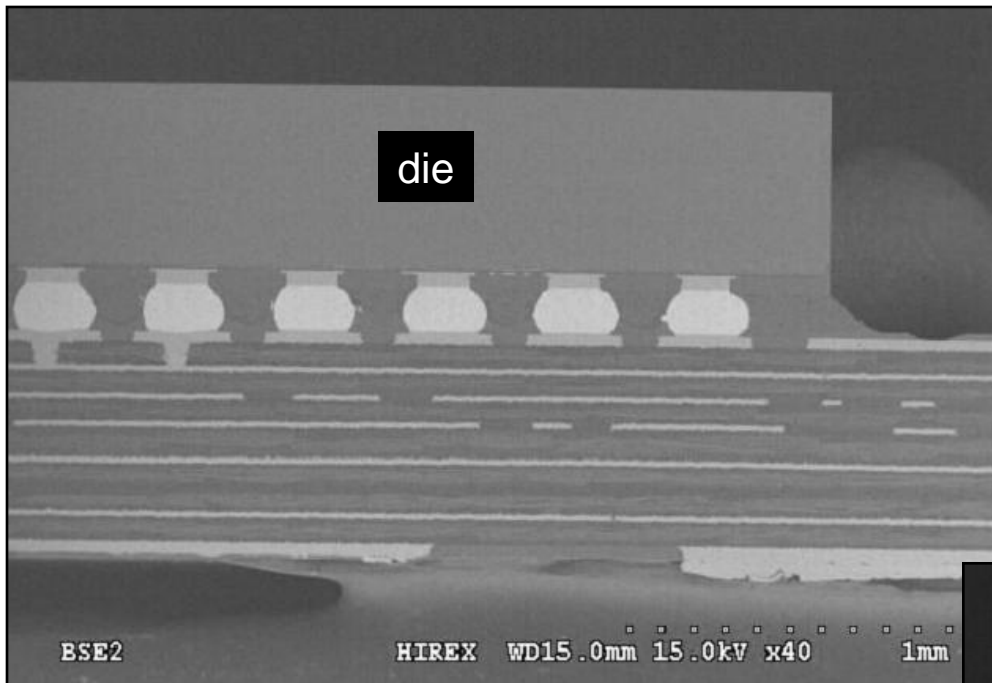
WL-CSP after underfill layer is removed. This picture shows the redistribution layer between the pads and the solder balls.

Pad
Redistribution
Copper pillar

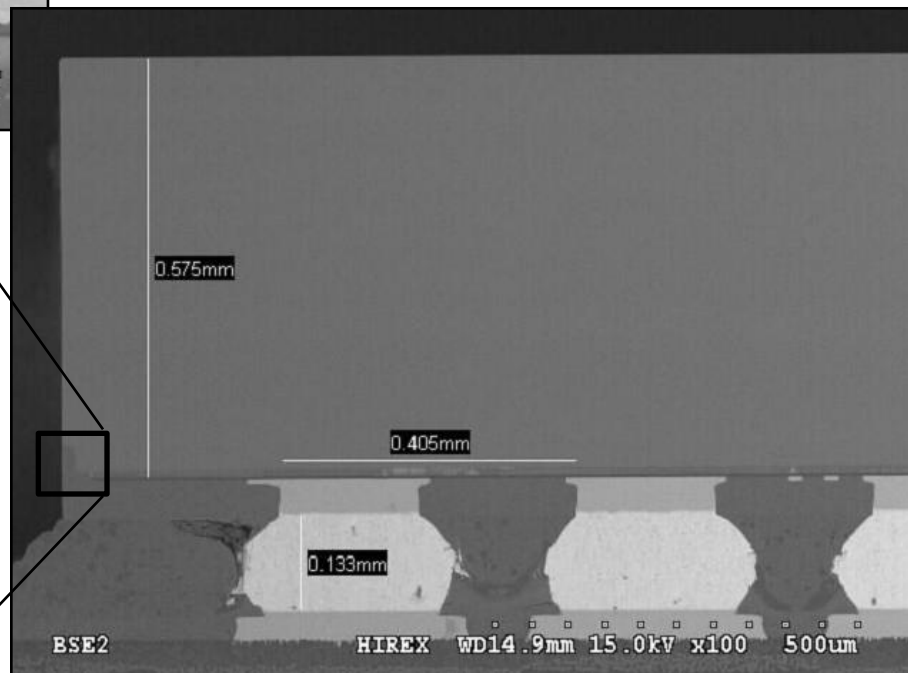
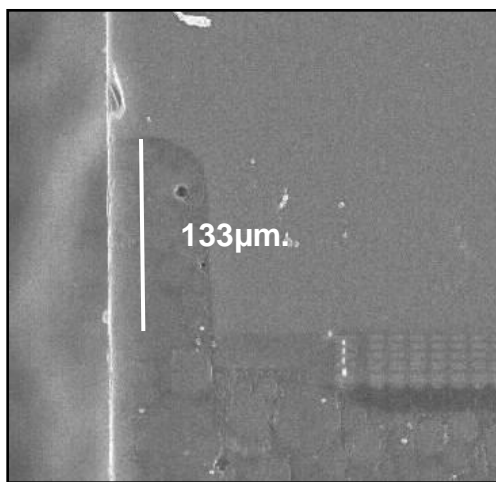


Die after redistribution layer removed.

Cross section cut



A bump pitch is 400 μ m.



A Pre-saw is realized and filled with a dielectric in order to enhance the die protection.

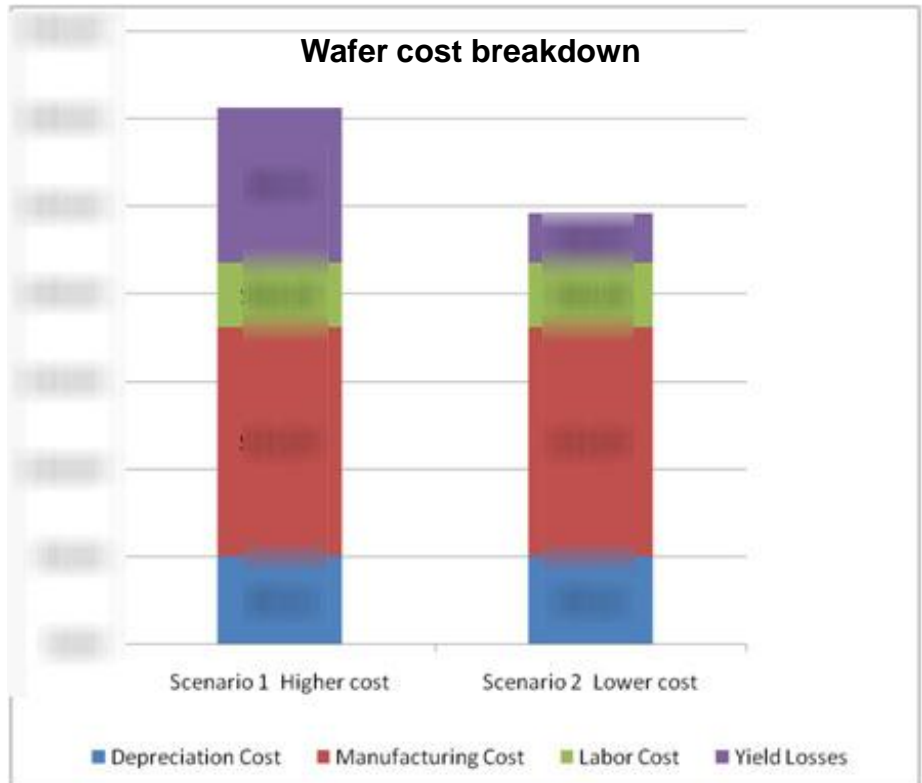
WL-CSP

- ➤ Additional BE - Cleaning
- ➤ Additional BE - Measurement
- ➤ Additional BE - Polyimide deposition (3μm)
- ➤ Additional BE - Pattern
- ➤ Additional BE - Cleaning
- ➤ Additional BE - Measurement
- ➤ UBM Barrier/Seed - TiN deposition
- ➤ UBM Barrier/Seed - Cu PVD deposition
- ➤ UBM Barrier/Seed - Reflow
- ➤ UBM Barrier/Seed - Cleaning
- ➤ UBM Barrier/Seed - Measurement
- ➤ Redistribution layer - Deposition
- ➤ Redistribution layer - Pattern
- ➤ Redistribution layer - Cure thick resin
- ➤ Redistribution layer - Cleaning
- ➤ Redistribution layer - Measurement
- ➤ Redistribution layer - Copper ECD 6μm
- ➤ Redistribution layer - PR Removal
- ➤ Redistribution layer - Cleaning

- The wafer is cleaned.
- A polyimide layer is deposited in order to increase the die protection against moisture and planarize the wafer.
- A thin barrier layer of titanium nitride is deposited.
- A thin Copper layer is deposited to serve as a seed layer.
- The mechanical stress is reduced by an annealing.
- A resin mask is patterned and the copper lines are electroplated.
- The development step is integrated in the Deposition step, cluster spin coating + dev equipment. The developer consumables are in the deposition step.
- The 6μm copper lines are electroplated.

	Scenario 1 Higher cost		Scenario 2 Lower cost	
	Cost	Breakdown	Cost	Breakdown
Depreciation Cost	10000	100%	10000	100%
Manufacturing Cost	100000	100%	100000	100%
Labor Cost	10000	100%	10000	100%
STEPS COST	110000	100%	110000	100%
Die cost	1000000		1000000	
Yield Losses	10000	100%	10000	100%
TOTAL	1100000	100%	1100000	100%
Manufacturing yield	100%		100%	

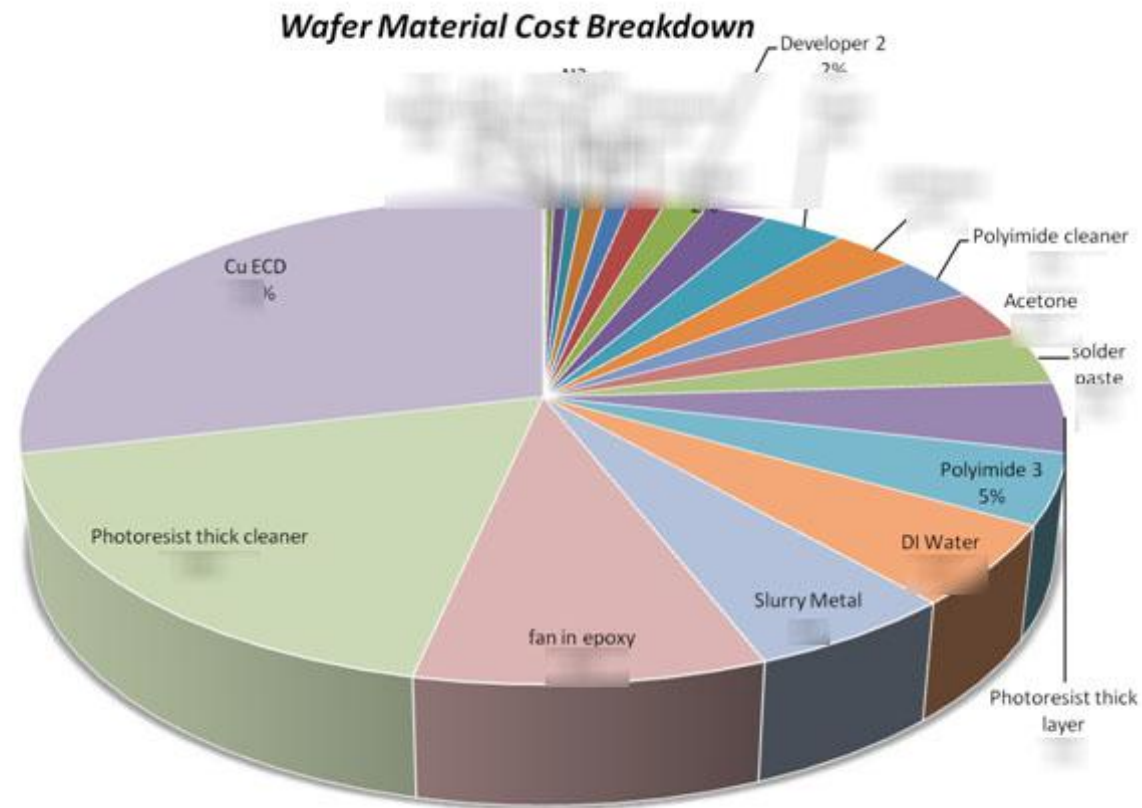
- The main part of the wafer cost is due to the Manufacturing Cost: between xx% and xx% of the cost.
- The yield losses is a major cost factor.
- The depreciation cost is between xx% and xx%.



Wafer cost per Consumable Family.

Material Name	Material Cost	Breakdown
SF6		
Cu Target		
CF4		
Al Etchant		
AP-309		
N2		
Photoresist		
Developer		
Ti Target		
Power		
O2 Plasma		
Polyimide cleaner		
Acetone		
solder paste		
Photoresist thick layer		
Polyimide		
DI Water		
Slurry Metal		
fan in epoxy		
Photoresist thick cleaner		
Cu ECD		
TOTAL		

- The cleaner used to etch the thick resin is expensive.
- Details of the material cost per step are given in the Excel spreadsheet.



Wafer cost per Material Family